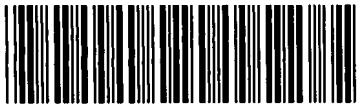


**Search Notes****Application/Control No.**

09/645,903

**Examiner**

Matthew W. Such

**Applicant(s)/Patent under Reexamination**

LI, LI

**Art Unit**

2891

**SEARCHED**

Class	Subclass	Date	Examiner
216	2,13-21	11/2/2007	MWS
134	2-3,28	11/2/2007	MWS
134	904	11/2/2007	MWS
257	745-757	11/2/2007	MWS
438	905-906	11/2/2007	MWS
438	700-702	11/2/2007	MWS
216	83,100	11/2/2007	MWS
216	108	11/2/2007	MWS
252	79.1-79.3	11/2/2007	MWS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Claims interference searched classes (see above)	11/2/2007	MWS	

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search	11/2/2007	MWS
EAST Classification Search	11/2/2007	MWS
IEEE Search (nitric and phosphorous)	11/2/2007	MWS
Google Scholar Search (semiconductor nitric phosphorous)	11/2/2007	MWS